Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/816,622	OOTSU ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

SEARCHED					
Class	Subclass	Date	Examiner		
216	11	2/13/2006	ВТ		
216	24	2/13/2006	ВТ		
216	96	2/13/2006	ВТ		
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INTERFERENCE SEARCHED					
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Search inventors' names and keyword using USPAT, USPG-PUB, JPO, EPO, DERWENT database	2/13/2006	ВТ
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